

November 2013

# FQA11N90\_F109

## N-Channel QFET® MOSFET

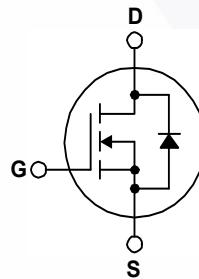
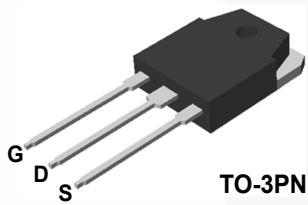
### 900 V, 11.4 A, 960 mΩ

#### Features

- 11.4 A, 900 V,  $R_{DS(on)}$  = 960 mΩ (Max.) @  $V_{GS} = 10$  V,  $I_D = 5.7$  A
- Low Gate Charge (Typ. 72 nC)
- Low Crss (Typ. 30 pF)
- 100% Avalanche Tested
- RoHS compliant

#### Description

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.



#### MOSFET Maximum Ratings $T_C = 25^\circ\text{C}$ unless otherwise noted.

Symbol	Parameter	FQA11N90_F109	Unit
$V_{DSS}$	Drain to Source Voltage	900	V
$I_D$	Drain Current	11.4	A
	- Continuous ( $T_C = 25^\circ\text{C}$ )	7.2	A
	- Continuous ( $T_C = 100^\circ\text{C}$ )		
$I_{DM}$	Drain Current	45.6	A
	- Pulsed		
$V_{GSS}$	Gate to Source Voltage	$\pm 30$	V
$E_{AS}$	Single Pulsed Avalanche Energy	1000	mJ
$I_{AR}$	Avalanche Current	11.4	A
$E_{AR}$	Repetitive Avalanche Energy	30	mJ
$dv/dt$	Peak Diode Recovery $dv/dt$	4.0	V/ns
$P_D$	Power Dissipation	300	W
	( $T_C = 25^\circ\text{C}$ )		
	- Derate above $25^\circ\text{C}$	2.38	W/ $^\circ\text{C}$
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to +150	$^\circ\text{C}$
$T_L$	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds	300	$^\circ\text{C}$

#### Thermal Characteristics

Symbol	Parameter	FQA11N90_F109	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max	0.42	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max	40	$^\circ\text{C/W}$

## Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FQA11N90	FQA11N90_F109	TO-3PN	Tube	N/A	30 units

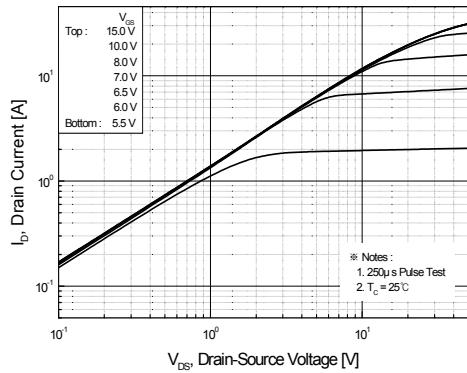
## Electrical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted.

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
<b>Off Characteristics</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{\text{GS}} = 0 \text{ V}$ , $I_D = 250 \mu\text{A}$	900	--	--	V
$\Delta \text{BV}_{\text{DSS}} / \Delta T_J$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu\text{A}$ , Referenced to $25^\circ\text{C}$	--	1.0	--	$\text{V}/^\circ\text{C}$
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{\text{DS}} = 900 \text{ V}$ , $V_{\text{GS}} = 0 \text{ V}$	--	--	10	$\mu\text{A}$
		$V_{\text{DS}} = 720 \text{ V}$ , $T_C = 125^\circ\text{C}$	--	--	100	$\mu\text{A}$
$I_{\text{GSSF}}$	Gate-Body Leakage Current, Forward	$V_{\text{GS}} = 30 \text{ V}$ , $V_{\text{DS}} = 0 \text{ V}$	--	--	100	nA
$I_{\text{GSSR}}$	Gate-Body Leakage Current, Reverse	$V_{\text{GS}} = -30 \text{ V}$ , $V_{\text{DS}} = 0 \text{ V}$	--	--	-100	nA
<b>On Characteristics</b>						
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}} = V_{\text{GS}}$ , $I_D = 250 \mu\text{A}$	3.0	--	5.0	V
$R_{\text{DS(on)}}$	Static Drain-Source On-Resistance	$V_{\text{GS}} = 10 \text{ V}$ , $I_D = 5.7 \text{ A}$	--	0.75	0.96	$\Omega$
$g_{\text{FS}}$	Forward Transconductance	$V_{\text{DS}} = 50 \text{ V}$ , $I_D = 5.7 \text{ A}$	--	12	--	S
<b>Dynamic Characteristics</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{\text{DS}} = 25 \text{ V}$ , $V_{\text{GS}} = 0 \text{ V}$ , $f = 1.0 \text{ MHz}$	--	2700	3500	pF
$C_{\text{oss}}$	Output Capacitance		--	260	340	pF
$C_{\text{rss}}$	Reverse Transfer Capacitance		--	30	40	pF
<b>Switching Characteristics</b>						
$t_{\text{d(on)}}$	Turn-On Delay Time	$V_{\text{DD}} = 450 \text{ V}$ , $I_D = 11.4 \text{ A}$ , $R_G = 25 \Omega$	--	65	140	ns
$t_r$	Turn-On Rise Time		--	135	280	ns
$t_{\text{d(off)}}$	Turn-Off Delay Time		--	165	340	ns
$t_f$	Turn-Off Fall Time		--	90	190	ns
$Q_g$	Total Gate Charge	$V_{\text{DS}} = 720 \text{ V}$ , $I_D = 11.4 \text{ A}$ , $V_{\text{GS}} = 10 \text{ V}$	--	72	94	nC
$Q_{\text{gs}}$	Gate-Source Charge		--	16	--	nC
$Q_{\text{gd}}$	Gate-Drain Charge		--	35	--	nC
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
$I_S$	Maximum Continuous Drain-Source Diode Forward Current	--	--	11.4	--	A
$I_{\text{SM}}$	Maximum Pulsed Drain-Source Diode Forward Current	--	--	45.6	--	A
$V_{\text{SD}}$	Drain-Source Diode Forward Voltage	$V_{\text{GS}} = 0 \text{ V}$ , $I_S = 11.4 \text{ A}$	--	--	1.4	V
$t_{\text{rr}}$	Reverse Recovery Time	$V_{\text{GS}} = 0 \text{ V}$ , $I_S = 11.4 \text{ A}$ , $dI_F / dt = 100 \text{ A}/\mu\text{s}$	--	850	--	ns
$Q_{\text{rr}}$	Reverse Recovery Charge		--	11.2	--	$\mu\text{C}$

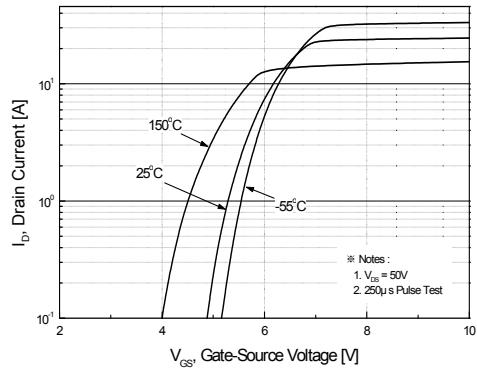
Notes :

1. Repetitive Rating : Pulse width limited by maximum junction temperature.
2.  $L = 15 \text{ mH}$ ,  $I_{AS} = 11.4 \text{ A}$ ,  $V_{DD} = 50 \text{ V}$ ,  $R_G = 25 \Omega$ , starting  $T_J = 25^\circ\text{C}$ .
3.  $I_{SD} \leq 11.4 \text{ A}$ ,  $di/dt \leq 200 \text{ A}/\mu\text{s}$ ,  $V_{DD} \leq \text{BV}_{\text{DSS}}$ , starting  $T_J = 25^\circ\text{C}$ .
4. Essentially independent of operating temperature.

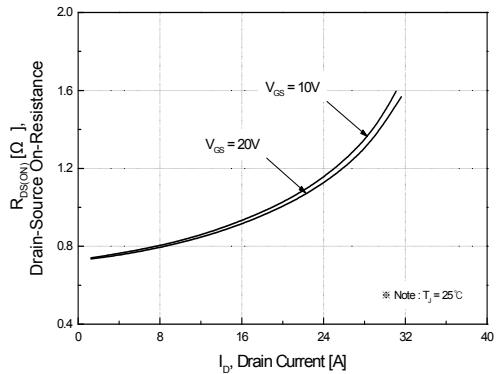
## Typical Characteristics



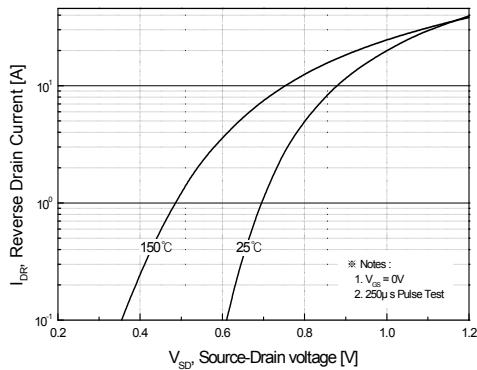
**Figure 1. On-Region Characteristics**



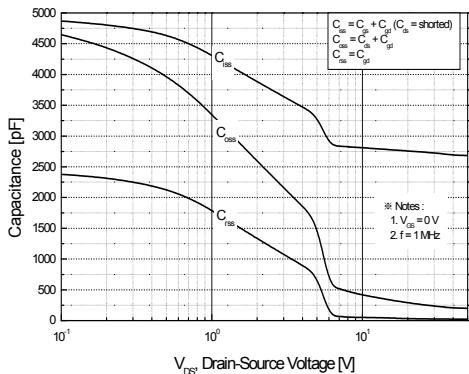
**Figure 2. Transfer Characteristics**



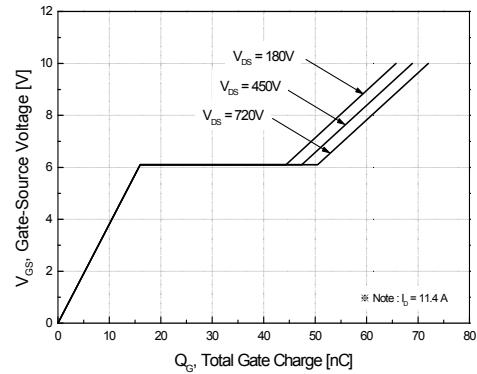
**Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage**



**Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature**

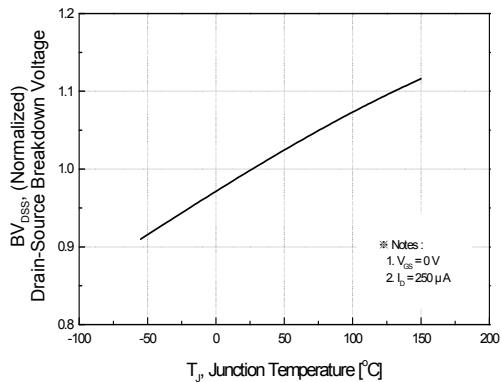


**Figure 5. Capacitance Characteristics**

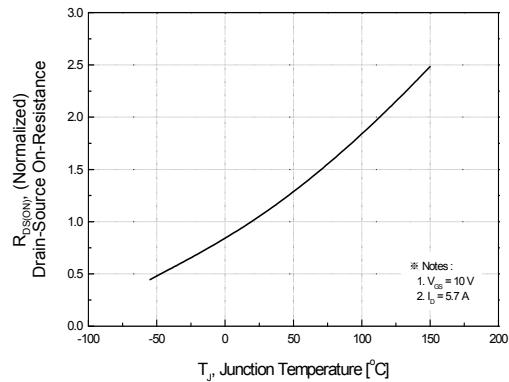


**Figure 6. Gate Charge Characteristics**

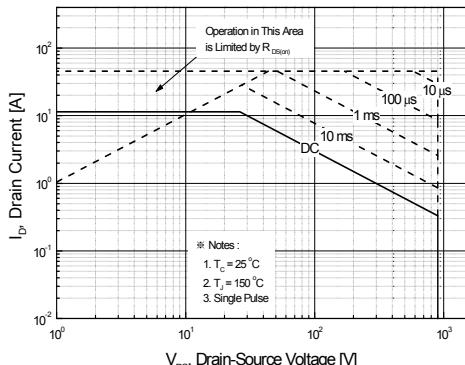
## Typical Characteristics (Continued)



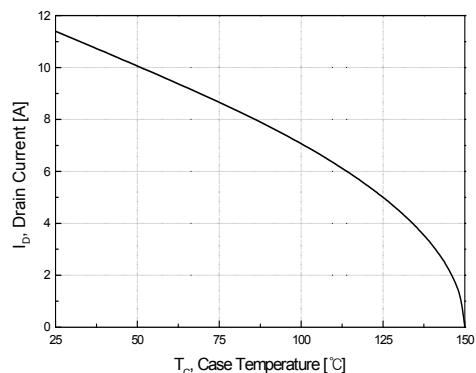
**Figure 7. Breakdown Voltage Variation vs. Temperature**



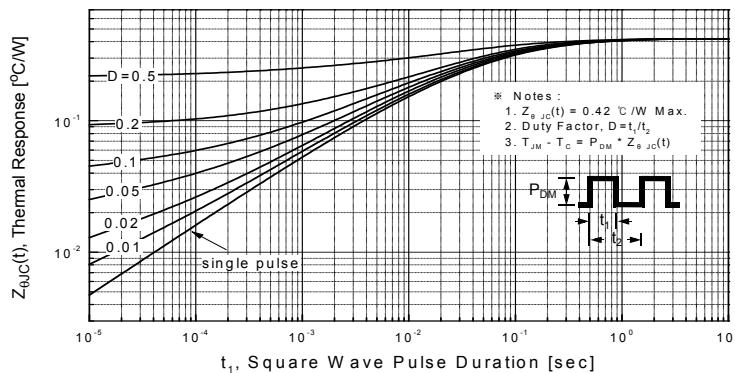
**Figure 8. On-Resistance Variation vs. Temperature**



**Figure 9. Maximum Safe Operating Area**



**Figure 10. Maximum Drain Current vs. Case Temperature**



**Figure 11. Transient Thermal Response Curve**

Figure 12. Gate Charge Test Circuit & Waveform

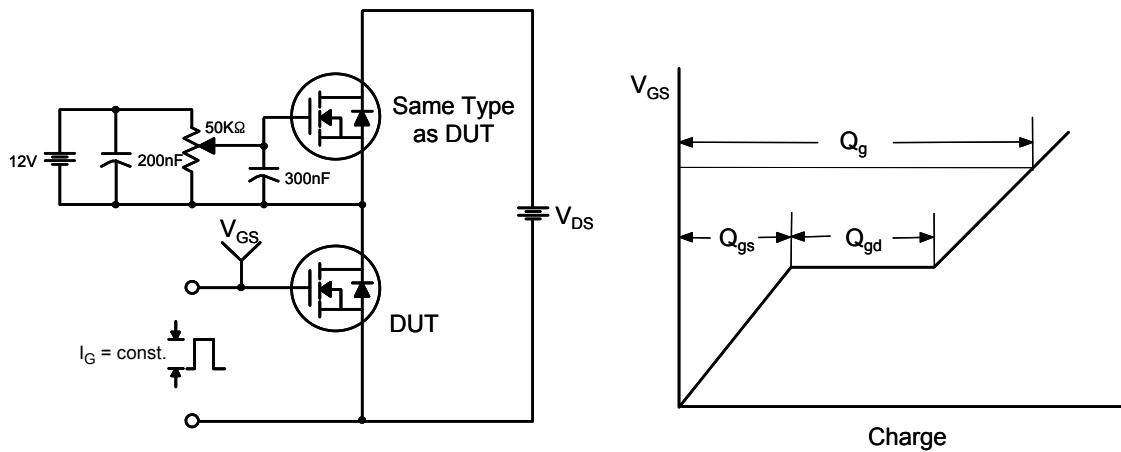


Figure 13. Resistive Switching Test Circuit & Waveforms

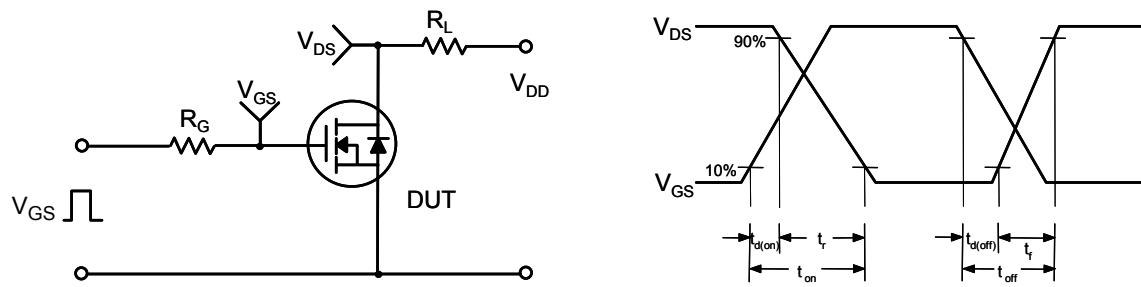


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms

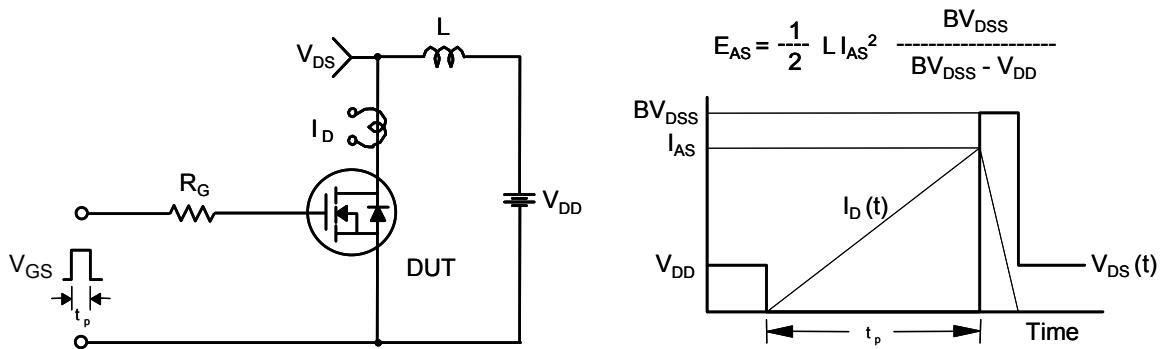
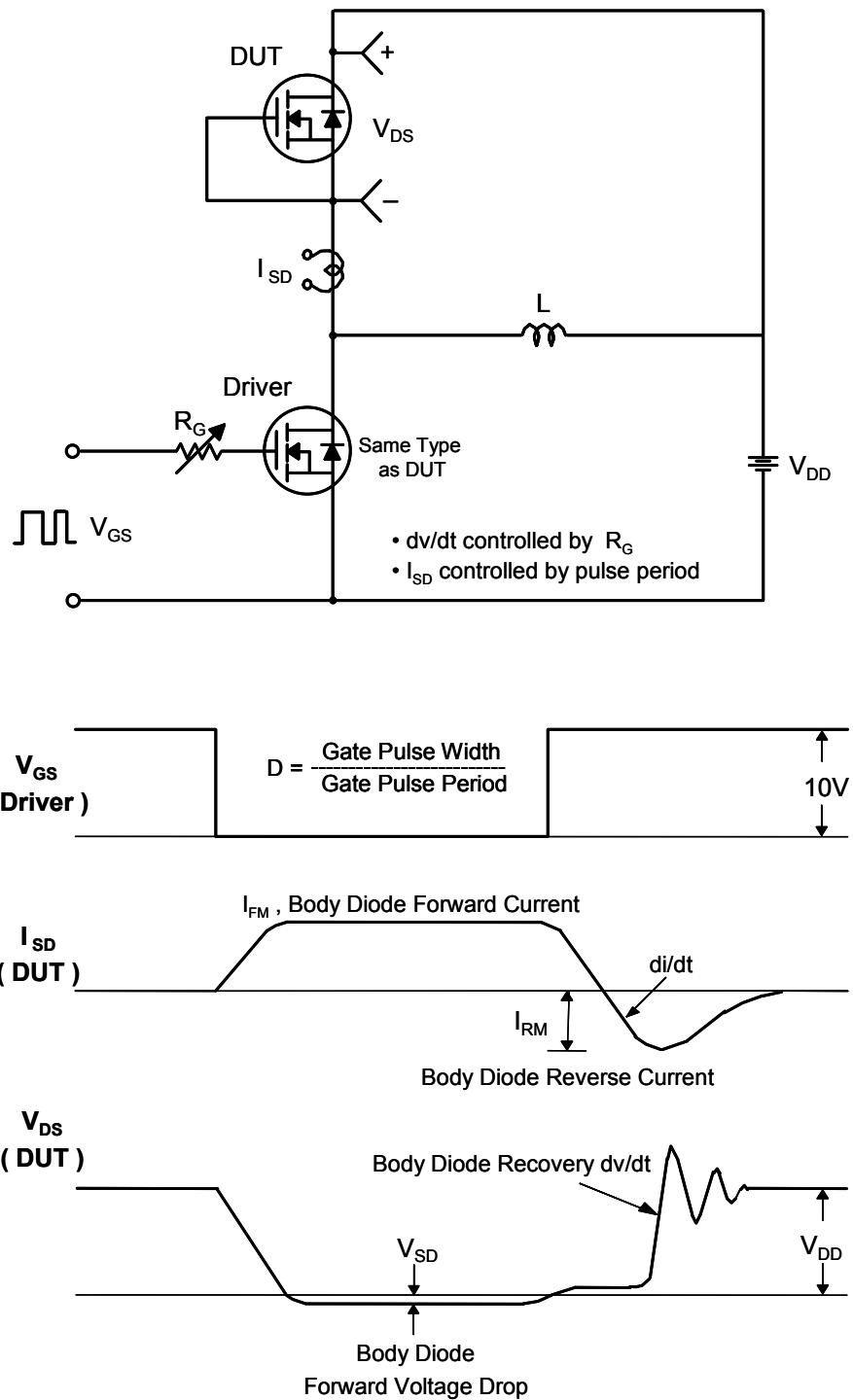
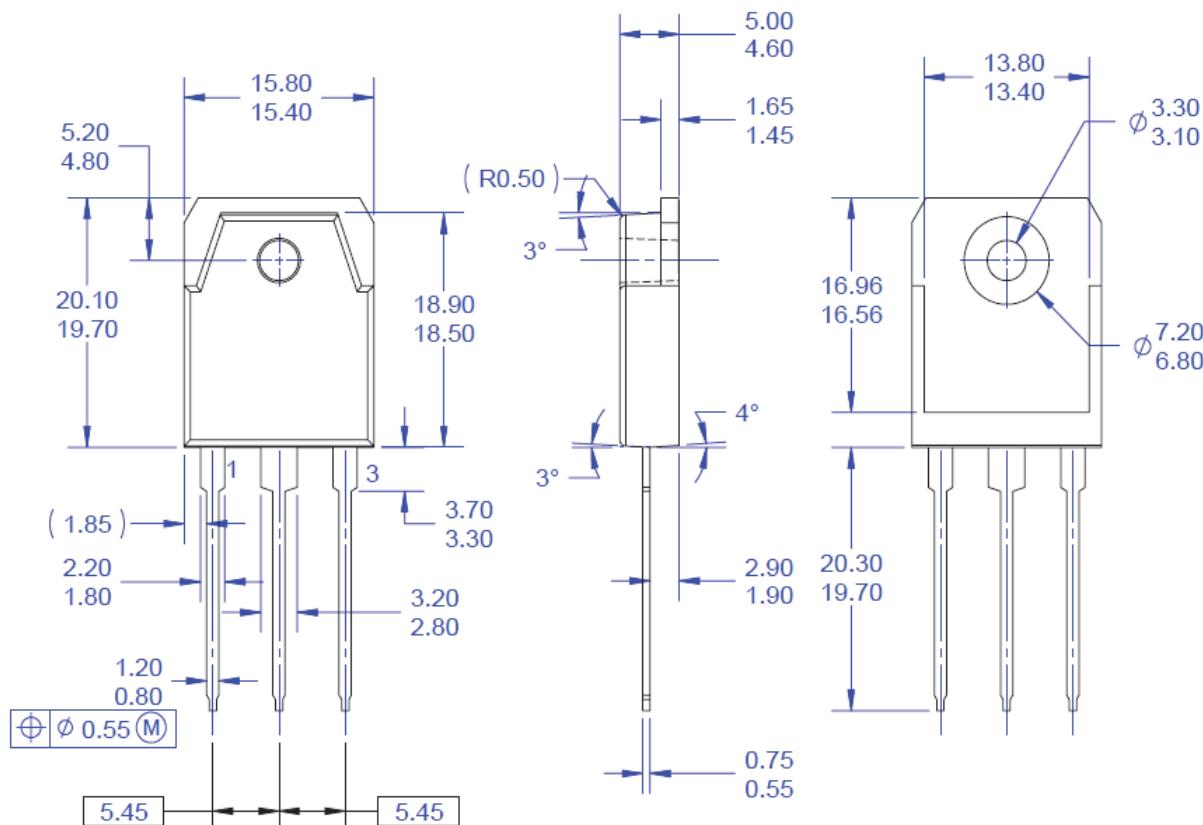


Figure 15. Peak Diode Recovery dv/dt Test Circuit &amp; Waveforms



### Mechanical Dimensions

TO-3PN 3L



#### NOTES: UNLESS OTHERWISE SPECIFIED

- A) THIS PACKAGE CONFORMS TO EIAJ SC-65 PACKAGING STANDARD.
  - B) ALL DIMENSIONS ARE IN MILLIMETERS.
  - C) DIMENSION AND TOLERANCING PER ASME14.5
  - D) DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.
  - E) THIS PACKAGE IS INTENDED ONLY FOR TO3PN.
  - F) DRAWING FILE NAME: TO3P03AREV4.

**Figure 16. 3LD, T03, Plastic, EIAJ SC-65**

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**Dimension in Millimeters**



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